

TOSHIBA Field Effect Transistor Silicon P/N Channel MOS Type

# SSM6L12TU

## High-Speed Switching Applications

- Optimum for high-density mounting in small packages
- Low ON-resistance Q1:  $R_{DS(ON)} = 180\text{m}\Omega$  (max) (@ $V_{GS} = 2.5\text{ V}$ )  
Q2:  $R_{DS(ON)} = 430\text{m}\Omega$  (max) (@ $V_{GS} = -2.5\text{ V}$ )

### Q1 Absolute Maximum Ratings ( $T_a = 25^\circ\text{C}$ )

| Characteristics      |       | Symbol    | Rating   | Unit |
|----------------------|-------|-----------|----------|------|
| Drain-source voltage |       | $V_{DS}$  | 30       | V    |
| Gate-source voltage  |       | $V_{GSS}$ | $\pm 12$ | V    |
| Drain current        | DC    | $I_D$     | 0.5      | A    |
|                      | Pulse | $I_{DP}$  | 1.5      |      |

### Q2 Absolute Maximum Ratings ( $T_a = 25^\circ\text{C}$ )

| Characteristics      |       | Symbol    | Rating   | Unit |
|----------------------|-------|-----------|----------|------|
| Drain-source voltage |       | $V_{DS}$  | -20      | V    |
| Gate-source voltage  |       | $V_{GSS}$ | $\pm 12$ | V    |
| Drain current        | DC    | $I_D$     | -0.5     | A    |
|                      | Pulse | $I_{DP}$  | -1.5     |      |

### Absolute Maximum Ratings (Q1,Q2 Common) ( $T_a = 25^\circ\text{C}$ )

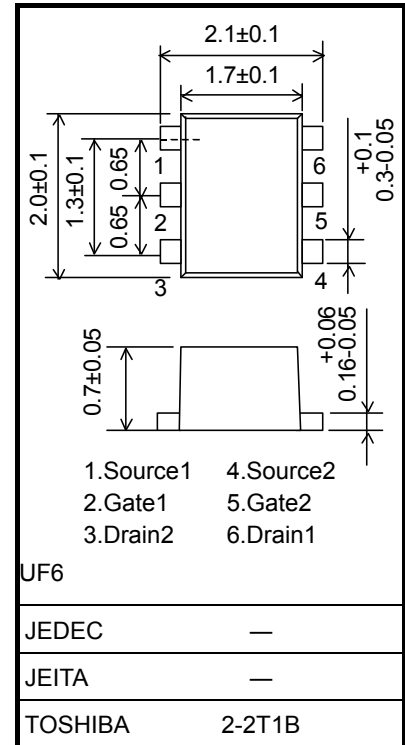
| Characteristics           | Symbol            | Rating     | Unit             |
|---------------------------|-------------------|------------|------------------|
| Power dissipation         | $P_D$<br>(Note 1) | 500        | mW               |
| Channel temperature       | $T_{ch}$          | 150        | $^\circ\text{C}$ |
| Storage temperature range | $T_{stg}$         | -55 to 150 | $^\circ\text{C}$ |

Note: Using continuously under heavy loads (e.g. the application of high temperature/current/voltage and the significant change in temperature, etc.) may cause this product to decrease in the reliability significantly even if the operating conditions (i.e. operating temperature/current/voltage, etc.) are within the absolute maximum ratings.

Please design the appropriate reliability upon reviewing the Toshiba Semiconductor Reliability Handbook ("Handling Precautions"/"Derating Concept and Methods") and individual reliability data (i.e. reliability test report and estimated failure rate, etc.).

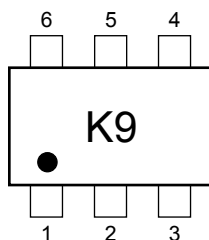
Note 1: Mounted on FR4 board. (total dissipation)  
( $25.4\text{ mm} \times 25.4\text{ mm} \times 1.6\text{ mm}$ , Cu Pad:  $645\text{ mm}^2$ )

Unit: mm

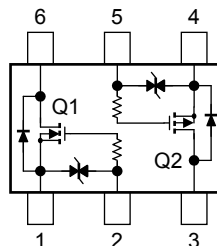


Weight: 7.0 mg (typ.)

### Marking



### Equivalent Circuit (top view)



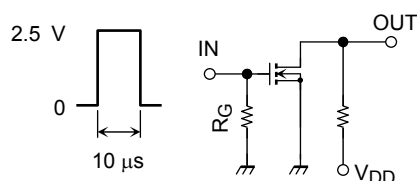
## Q1 Electrical Characteristics (Ta = 25°C)

| Characteristics                | Symbol        | Test Condition                                                                                             | Min | Typ. | Max     | Unit             |
|--------------------------------|---------------|------------------------------------------------------------------------------------------------------------|-----|------|---------|------------------|
| Gate leakage current           | $I_{GSS}$     | $V_{GS} = \pm 12 \text{ V}, V_{DS} = 0$                                                                    | —   | —    | $\pm 1$ | $\mu\text{A}$    |
| Drain-source breakdown voltage | $V_{(BR)DSS}$ | $I_D = 1 \text{ mA}, V_{GS} = 0$                                                                           | 30  | —    | —       | V                |
|                                | $V_{(BR)DSX}$ | $I_D = 1 \text{ mA}, V_{GS} = -12 \text{ V}$                                                               | 18  | —    | —       |                  |
| Drain cut-off current          | $I_{DSS}$     | $V_{DS} = 30 \text{ V}, V_{GS} = 0$                                                                        | —   | —    | 1       | $\mu\text{A}$    |
| Gate threshold voltage         | $V_{th}$      | $V_{DS} = 3 \text{ V}, I_D = 0.1 \text{ mA}$                                                               | 0.5 | —    | 1.1     | V                |
| Forward transfer admittance    | $ Y_{fs} $    | $V_{DS} = 3 \text{ V}, I_D = 0.25 \text{ A}$ (Note 2)                                                      | 1.0 | 2.0  | —       | S                |
| Drain-source on-resistance     | $R_{DS(ON)}$  | $I_D = 0.50 \text{ A}, V_{GS} = 4.5 \text{ V}$ (Note 2)                                                    | —   | 120  | 145     | $\text{m}\Omega$ |
|                                |               | $I_D = 0.25 \text{ A}, V_{GS} = 2.5 \text{ V}$ (Note 2)                                                    | —   | 140  | 180     |                  |
| Input capacitance              | $C_{iss}$     | $V_{DS} = 10 \text{ V}, V_{GS} = 0, f = 1 \text{ MHz}$                                                     | —   | 245  | —       | pF               |
| Reverse transfer capacitance   | $C_{rss}$     | $V_{DS} = 10 \text{ V}, V_{GS} = 0, f = 1 \text{ MHz}$                                                     | —   | 33   | —       | pF               |
| Output capacitance             | $C_{oss}$     | $V_{DS} = 10 \text{ V}, V_{GS} = 0, f = 1 \text{ MHz}$                                                     | —   | 41   | —       | pF               |
| Switching time                 | Turn-on time  | $V_{DD} = 10 \text{ V}, I_D = 0.25 \text{ A},$<br>$V_{GS} = 0 \text{ to } 2.5 \text{ V}, R_G = 4.7 \Omega$ | —   | 9    | —       | ns               |
|                                | Turn-off time |                                                                                                            | —   | 15   | —       |                  |

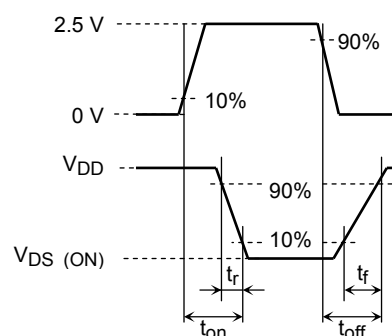
Note 2: Pulse test

## Switching Time Test Circuit

(a) Test Circuit



$V_{DD} = 10 \text{ V}$   
 $R_G = 4.7 \Omega$   
Duty  $\leq 1\%$   
 $V_{IN}$ :  $t_r, t_f < 5 \text{ ns}$   
Common Source  
 $T_a = 25^\circ\text{C}$

(b)  $V_{IN}$ (c)  $V_{OUT}$ 

## Precaution

$V_{th}$  can be expressed as the voltage between gate and source when the low operating current value is  $I_D = 100 \mu\text{A}$  for this product. For normal switching operation,  $V_{GS(ON)}$  requires a higher voltage than  $V_{th}$  and  $V_{GS(OFF)}$  requires a lower voltage than  $V_{th}$ .

(The relationship can be established as follows:  $V_{GS(OFF)} < V_{th} < V_{GS(ON)}$ )

Please take this into consideration when using the device.

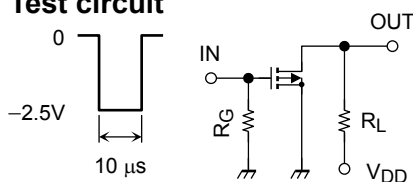
## Q2 Electrical Characteristics (Ta = 25°C)

| Characteristics                | Symbol        | Test Condition                                                                        | Min  | Typ. | Max     | Unit      |
|--------------------------------|---------------|---------------------------------------------------------------------------------------|------|------|---------|-----------|
| Gate leakage current           | $I_{GSS}$     | $V_{GS} = \pm 12V, V_{DS} = 0$                                                        | —    | —    | $\pm 1$ | $\mu A$   |
| Drain-source breakdown voltage | $V_{(BR)DSS}$ | $I_D = -1 mA, V_{GS} = 0$                                                             | -20  | —    | —       | V         |
|                                | $V_{(BR)DSX}$ | $I_D = -1 mA, V_{GS} = +12 V$                                                         | -8   | —    | —       |           |
| Drain cut-off current          | $I_{DSS}$     | $V_{DS} = -20 V, V_{GS} = 0$                                                          | —    | —    | -1      | $\mu A$   |
| Gate threshold voltage         | $V_{th}$      | $V_{DS} = -3 V, I_D = -0.1 mA$                                                        | -0.5 | —    | -1.1    | V         |
| Forward transfer admittance    | $ Y_{fs} $    | $V_{DS} = -3 V, I_D = -0.25 A$ (Note 3)                                               | 0.65 | 1.3  | —       | S         |
| Drain-source on-resistance     | $R_{DS(ON)}$  | $I_D = -0.25 A, V_{GS} = -4 V$ (Note 3)                                               | —    | 210  | 260     | $m\Omega$ |
|                                |               | $I_D = -0.25 A, V_{GS} = -2.5 V$ (Note 3)                                             | —    | 310  | 430     |           |
| Input capacitance              | $C_{iss}$     | $V_{DS} = -10 V, V_{GS} = 0, f = 1 MHz$                                               | —    | 218  | —       | pF        |
| Reverse transfer capacitance   | $C_{rss}$     | $V_{DS} = -10 V, V_{GS} = 0, f = 1 MHz$                                               | —    | 42   | —       | pF        |
| Output capacitance             | $C_{oss}$     | $V_{DS} = -10 V, V_{GS} = 0, f = 1 MHz$                                               | —    | 52   | —       | pF        |
| Switching time                 | Turn-on time  | $V_{DD} = -10 V, I_D = -0.25 A,$<br>$V_{GS} = 0 \text{ to } -2.5 V, R_G = 4.7 \Omega$ | —    | 16   | —       | ns        |
|                                | Turn-off time |                                                                                       | —    | 15   | —       |           |

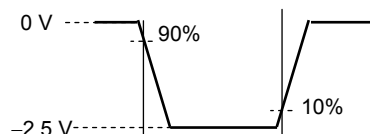
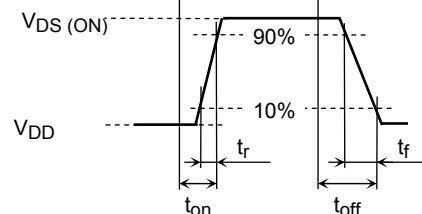
Note3: Pulse test

## Switching Time Test Circuit

## (a) Test circuit



$V_{DD} = -10 V$   
 $R_G = 4.7 \Omega$   
Duty  $\leq 1\%$   
 $V_{IN}$ :  $t_r, t_f < 5 ns$   
Common Source  
 $T_a = 25^\circ C$

(b)  $V_{IN}$ (c)  $V_{OUT}$ 

## Precaution

$V_{th}$  can be expressed as the voltage between gate and source when the low operating current value is  $I_D = -100 \mu A$  for this product. For normal switching operation,  $V_{GS(ON)}$  requires a higher voltage than  $V_{th}$  and  $V_{GS(OFF)}$  requires a lower voltage than  $V_{th}$ .

(The relationship can be established as follows:  $V_{GS(OFF)} < V_{th} < V_{GS(ON)}$ )

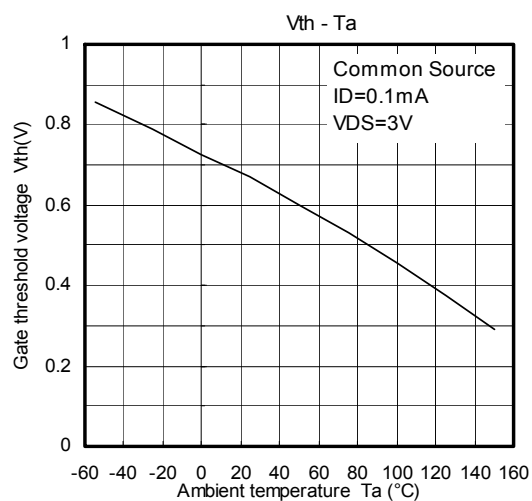
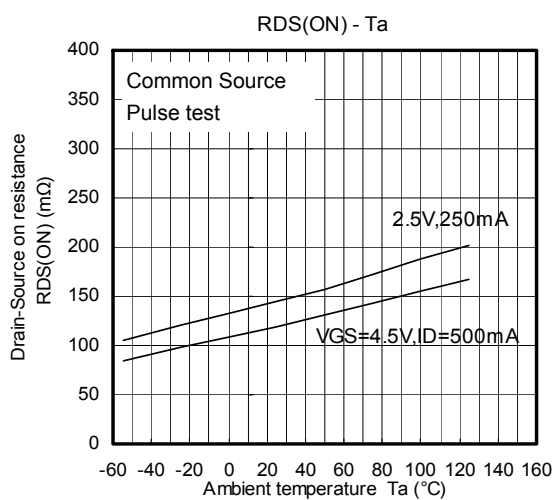
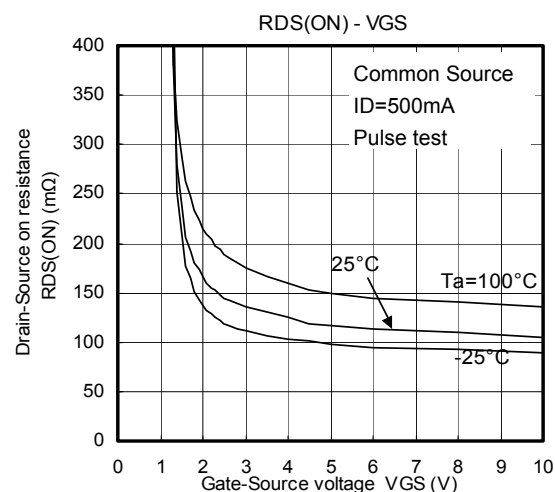
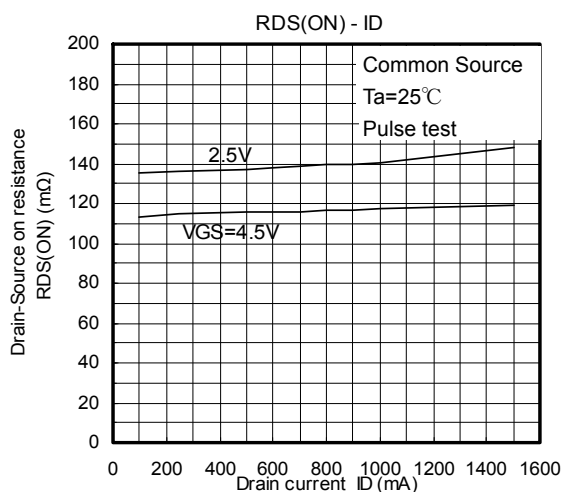
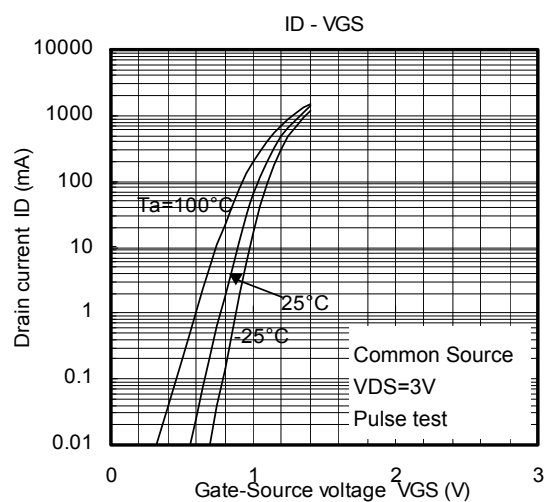
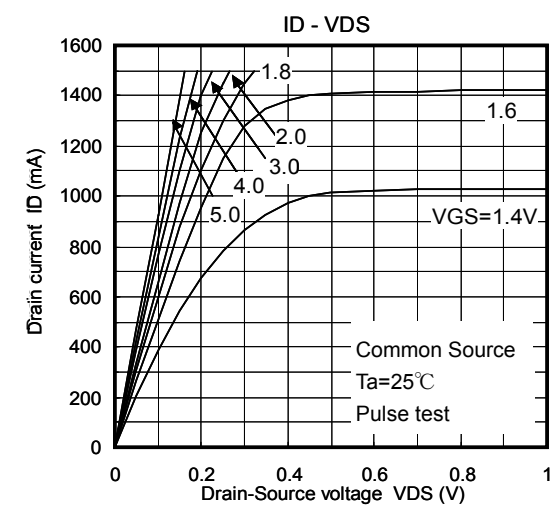
Please take this into consideration when using the device.

## Handling Precaution

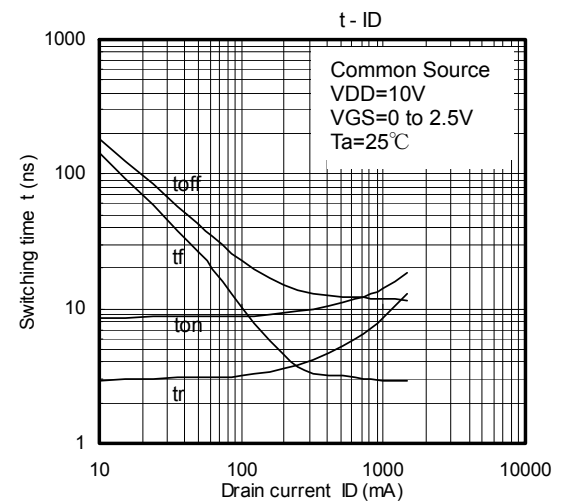
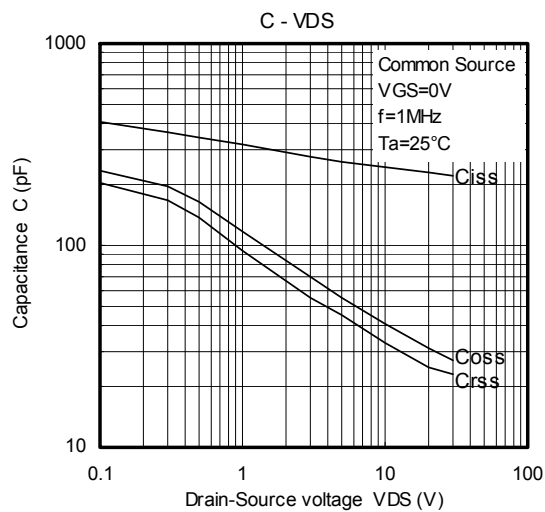
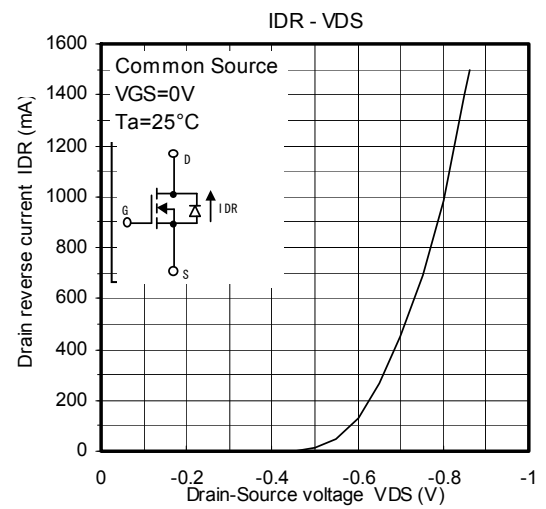
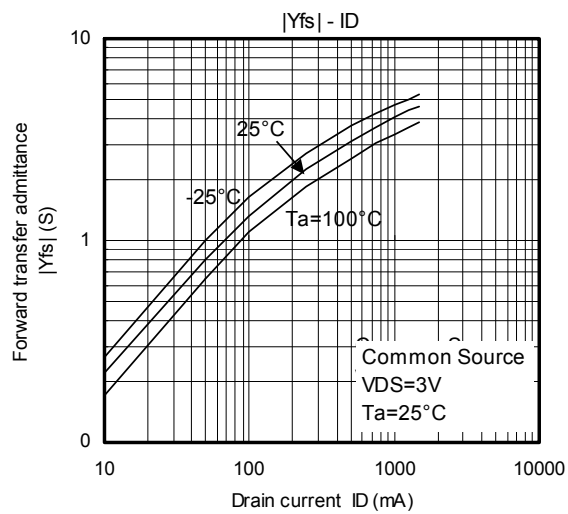
When handling individual devices (which are not yet mounted on a circuit board), be sure that the environment is protected against electrostatic electricity. Operators should wear anti-static clothing, and containers and other objects that come into direct contact with devices should be made of anti-static materials.

Thermal resistance  $R_{th(ch-a)}$  and power dissipation  $P_D$  vary depending on board material, board area, board thickness and pad area. When using this device, please take heat dissipation into consideration

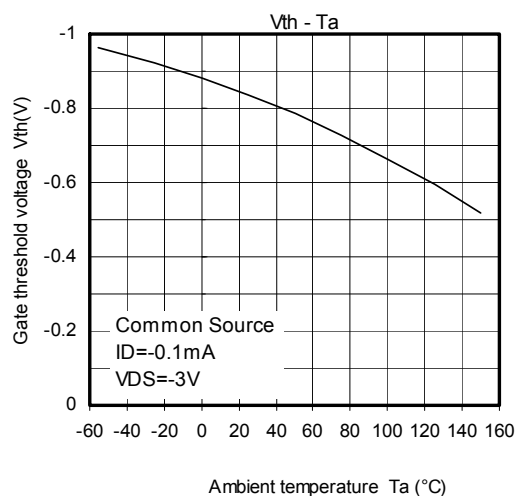
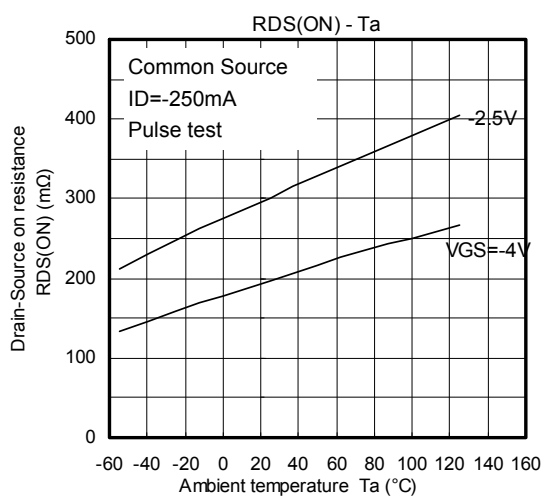
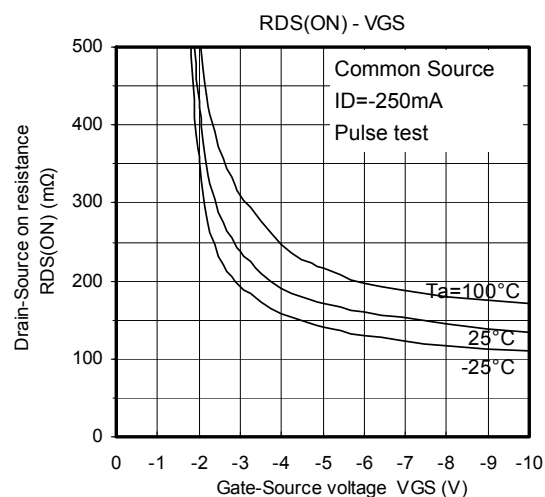
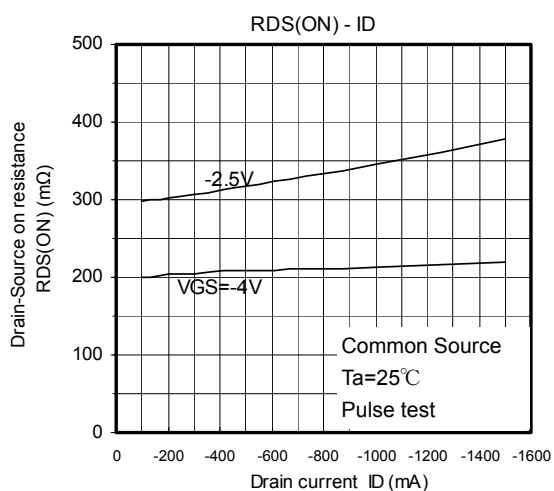
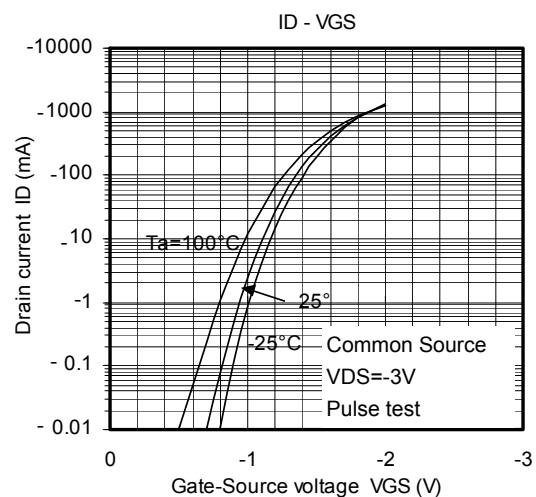
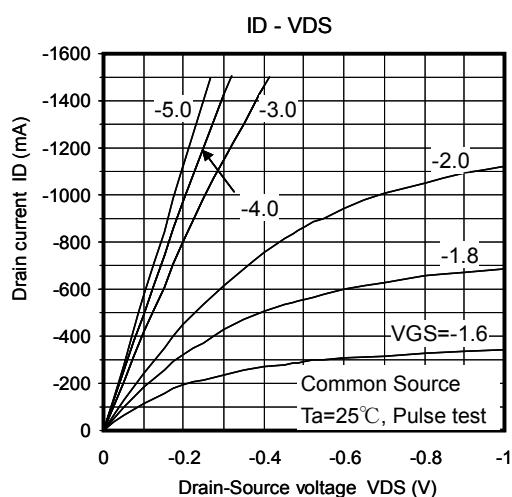
## Q1(Nch MOS FET)



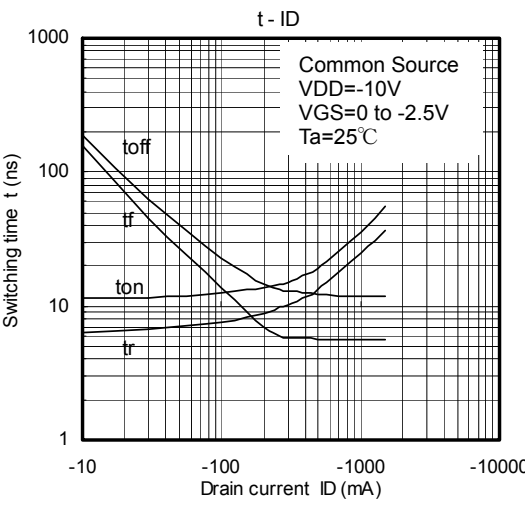
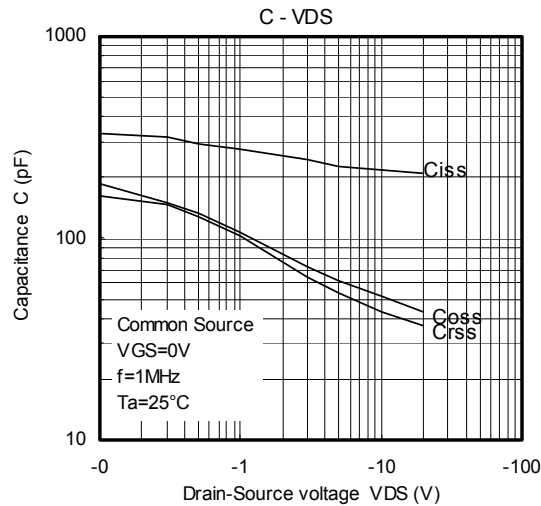
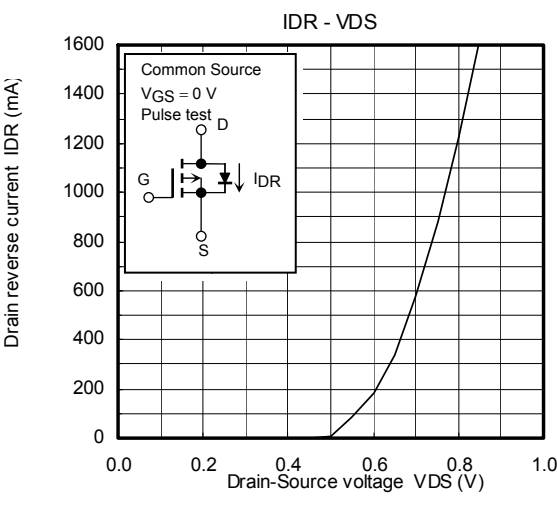
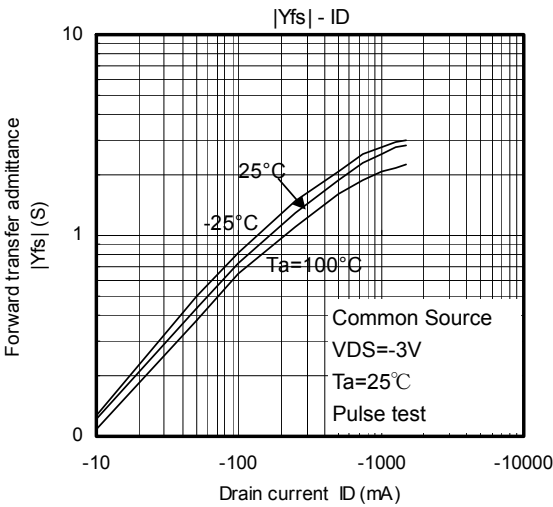
## Q1(Nch MOS FET)

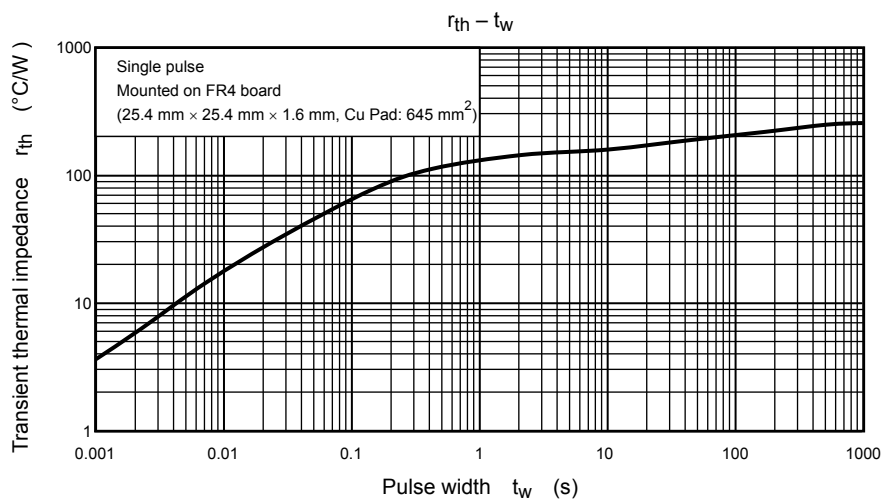
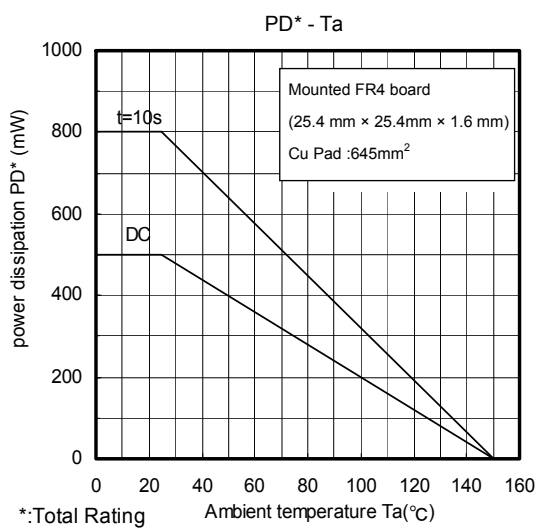


## Q2(Pch MOS FET)



Q2(Pch MOS FET)





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